

Defect-oriented test generation using probabilistic estimation

Cibakova, Tatiana; Fischerova, Maria; Gramatova, Elena; Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes**
Proceedings of the 8th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2001 : Zakopane, Poland, 21-23 June 2000 2001 / p. 131-136 : ill

Finite state machines with datapath partitioning for low power synthesis

Sudnitsõn, Aleksander Proceedings of the 8th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2001 : Zakopane, Poland, 21-23 June 2000 2001 / p. 163-168 : ill

Laboratory training for teaching design and test of digital circuits

Jutman, Artur; Ubar, Raimund-Johannes Proceedings of the 8th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2001 : Zakopane, Poland, 21-23 June 2000 2001 / p. 521-524 : ill <https://pld.ttu.ee/~artur/papers/TestLabs-MIXDES01.pdf>